

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination HECKMEIER ET AL.	
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	C	US-5334327	08-1994	Gray et al.	252/299.67
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**NON-PATENT DOCUMENTS**

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	U	English translation for JP 09-157654 by computer, <a href="http://www6.ipdl.jpo.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&amp;N0120=01&amp;N2001=2&amp;N3001=H09-157654">http://www6.ipdl.jpo.go.jp/Tokujitu/PAJdetail.ipdl?N0000=60&amp;N0120=01&amp;N2001=2&amp;N3001=H09-157654</a>
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